


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/922,178	LEWIS, CRAIG	
	Examiner	Art Unit	
	Minh Dieu Nguyen	2137	

SEARCHED			
Class	Subclass	Date	Examiner
713	184, 200, 202	7/14/2005	MDN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Updated search on EAST (US-PAT; US-PGPUB; EPO; JPO; DERWENT; IBM-TDB)	7/14/2005	MDN